

ICR E150 set

Near-Field Microprobe E-field 7 MHz up to 3 GHz



Short description

The near-field microprobe is designed for a high-resolution measurement of electrical near fields. With the ICR E probe the following measurements can be performed:

- Surface Scan via IC according to IEC 61967-3
- Volumenscan via IC
- Pin Scan

The measuring electrode at the ICR RF probe head is horizontally aligned to the measurement surface. A preamplifier is integrated into the probe housing and powered by the enclosed Bias-Tee.

The ICR near-field probes undergo a quality check before they are delivered. Different reference setup measurements are performed and resulting correction lines are generated. Two different correction lines are determined – a standardized correction line and an E-field correction line.

Attention: Due to its construction, the ICR probe is sensitive to shock and comes with a protective cap for transport and handling.

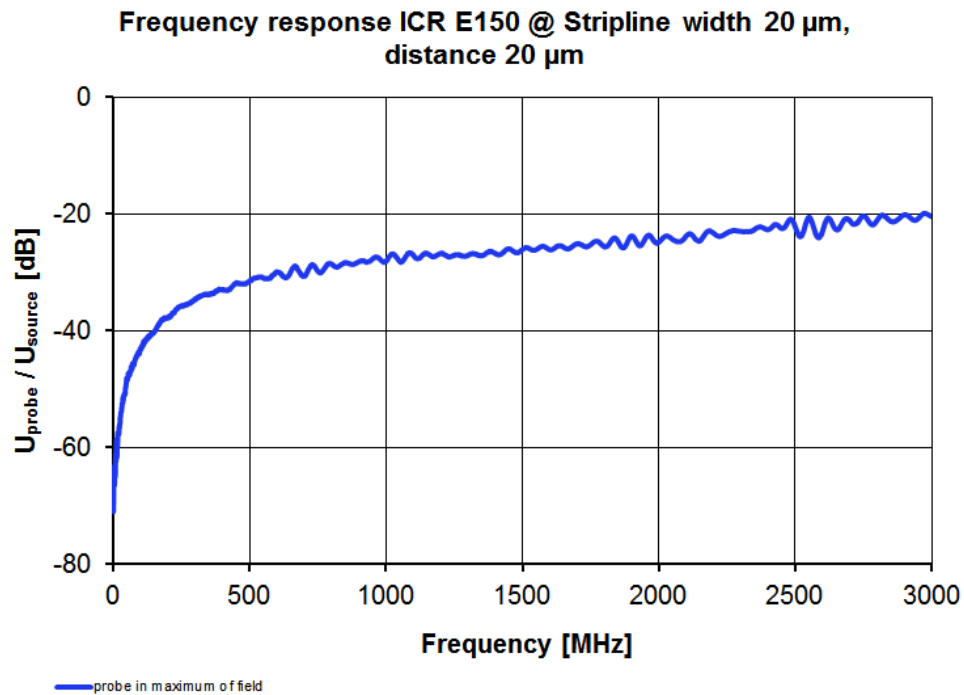
Scope of delivery

- 1x ICR E150, Near-Field Microprobe E-field 7 MHz to 3 GHz
- 1x BT 706, Bias Tee for Langer probes
- 1x SMA-SMA RA, Cable SMA-SMA, right angle
- 1x ICR-C, ICR Certificate
- 1x ICR Corr, Correction Curves ICR / USB
- 1x NT FRI EU, Power Supply Unit
- 1x ICR case1, System Case

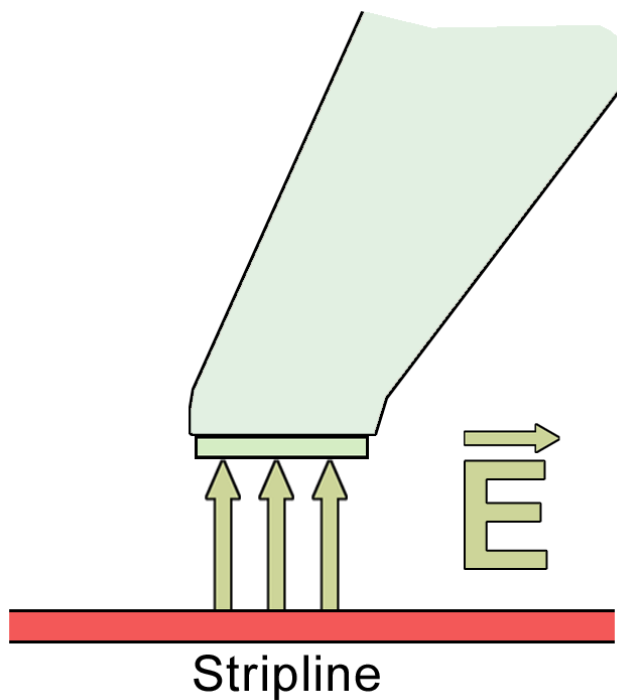
Technical parameters

Frequency range	7 MHz ... 3 GHz
Resolution	65 µm
Electrode surface area	(150 x 35) µm

Frequency response

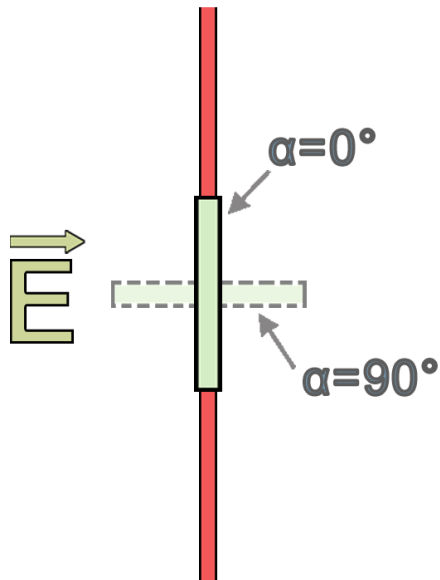


Measuring principles



Design, view 1

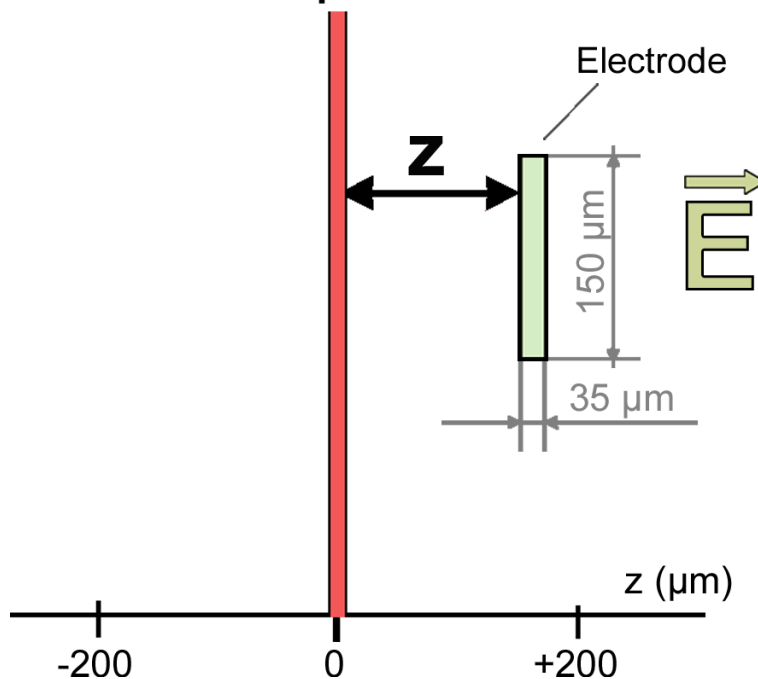
Stripline



f, α ...variable

Design, view 2

Stripline

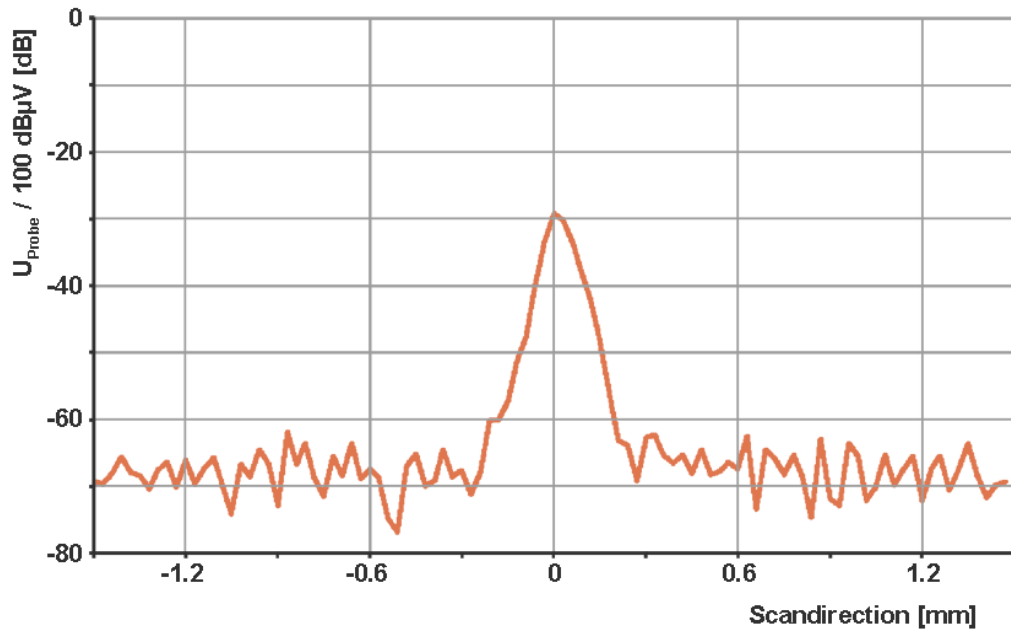


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Transverse profile



ICR E150

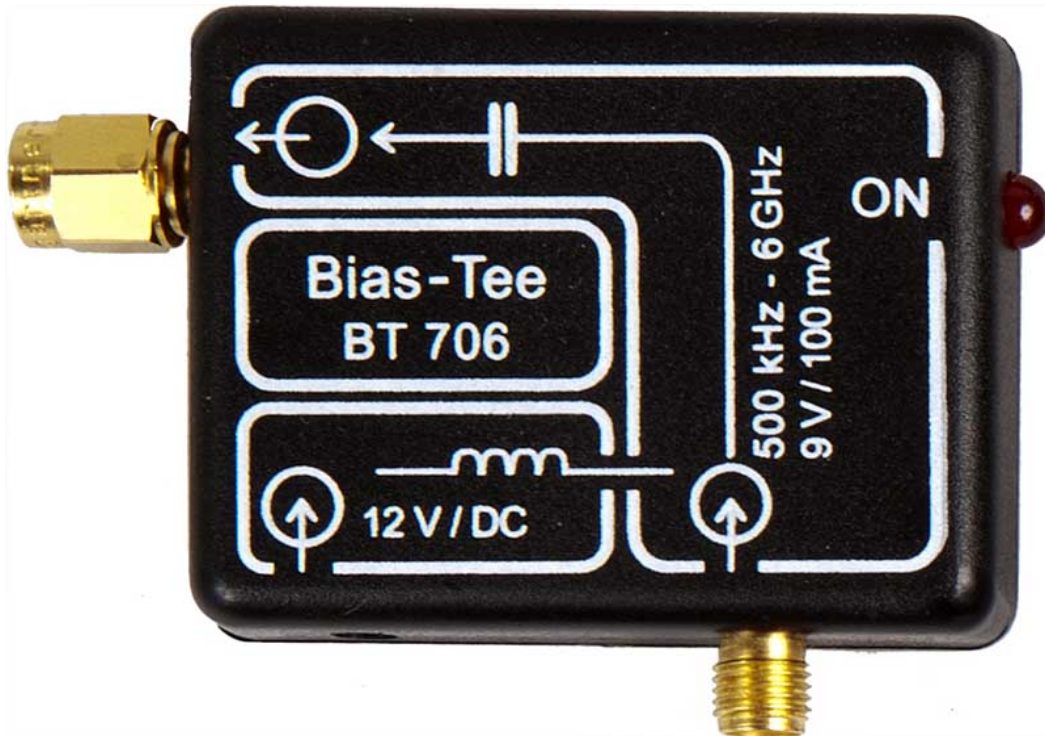


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BT 706 bias tee



Scope of delivery

